

<b>Notice of References Cited</b>	Application/Control No. 10/784,487	Applicant(s)/Patent Under Reexamination MOYER ET AL.	
	Examiner Khanh B. Duong	Art Unit 2822	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,349,371 a	09-1994	Fong, Kwang-Chien	345/166
*	B	US-5,463,387 a	10-1995	Kato, Takaaki	341/31
*	C	US-2002/0080117 a1	06-2002	Son et al.	345/163
*	D	US-2003/0112220 a1	06-2003	Yang et al.	345/156
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP360035244A	02-1985	JAPAN	NAKAMURA ET AL.	
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.